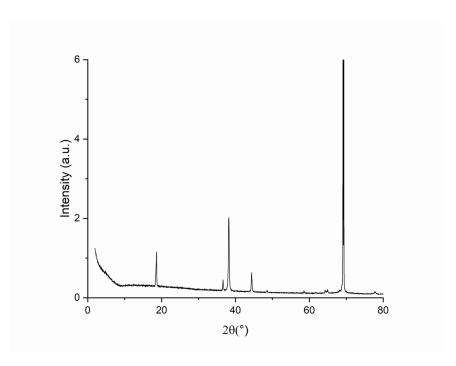
## **Supplemental information**

**Electronic properties of lithium-ion** 

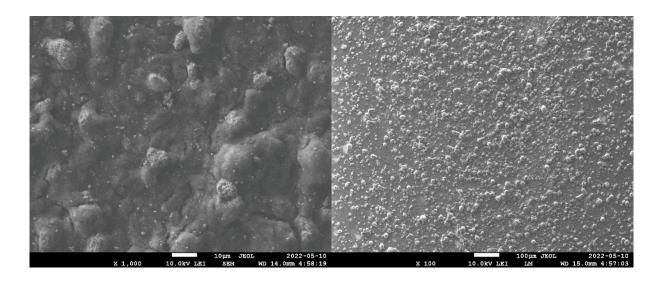
battery cathodes studied in ion-gated

transistor configuration

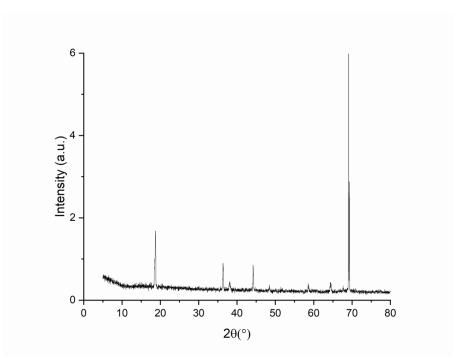
Federico Poli, José Ramón Herrera, Tian Lan, Prajwal Kumar, Clara Santato, and Francesca Soavi



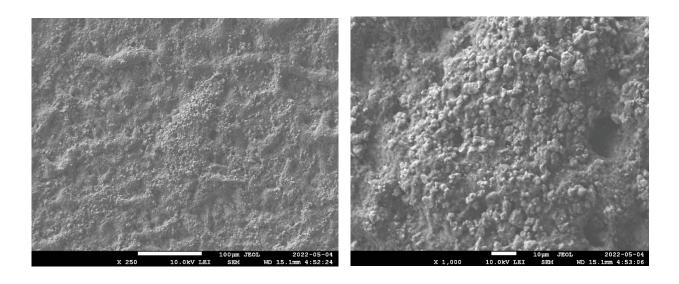
**Figure S1.** XRD pattern of NMC532 composite deposited on SiO<sub>2</sub>/Si. Related to Figure 2 and Figure 3.



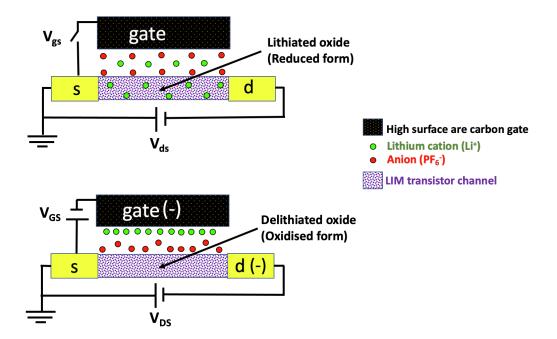
**Figure S2.** SEM images of NMC532 composite deposited on SiO<sub>2</sub>/Si substrate at different magnifications. Related to Figure 2 and Figure 3.



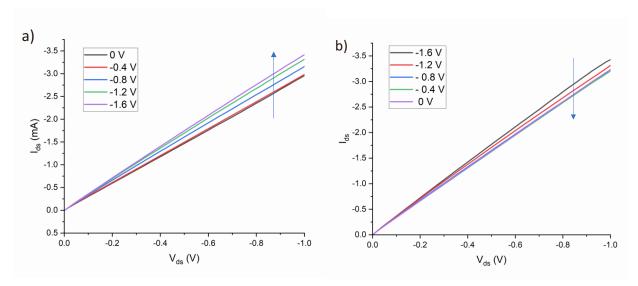
**Figure S3.** XRD pattern of LNMO composite deposited on SiO<sub>2</sub>/Si substrate. Related to Figure 2 and Figure 4.



**Figure S4.** SEM images of LNMO composite deposited on SiO<sub>2</sub>/Si substrate at different magnifications. Related to Figure 2 and Figure 4.



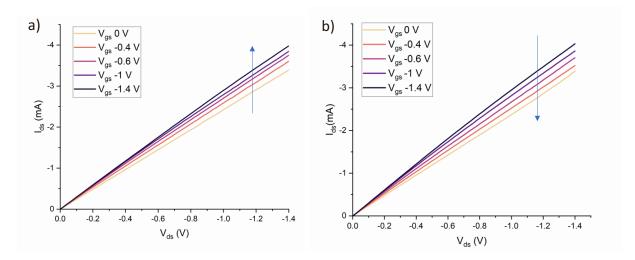
**Figure S5**. Working principle of the IGT (top) without  $V_{gs}$  and (bottom) with  $V_{gs}$  bias applied. Before application of  $V_{gs}$ , the channel is lithiated (top). When a negative  $V_{gs}$  is applied, the channel is delithiated (bottom):  $Li^+$  ions move towards the carbon gate, where an electrical double layer forms at the carbon/electrolyte interface. The value of  $I_{ds}$  depends on  $V_{gs}$  (i.e. on the state-of-charge of the LIM). Related to Figure 2.



**Figure S6.** Output curves of NMC532- based IGTs at  $V_{ds}$  scan rate of 20 mV s<sup>-1</sup> for: **a)** forward scan with  $V_{gs}$  from 0 to -1.6 V, corresponding to potentials from 3 V to 4.6 V vs  $Li^+/Li$ ; **b)** reverse scan with  $V_{gs}$  from -1.6 V to 0 V, corresponding to potentials from 4.6 V to 3 V vs  $Li^+/Li$ . Related to Figure 2 and Figure 3. Related to Figure 2 and Figure 3.

**Table S1.** NMC532 composite electronic resistance evaluated from the output tests at different  $V_{gs}$  during forward and backward  $V_{ds}$  sweeps at 20 mV s<sup>-1</sup>, reported in Fig. S6. Related to Figure 2 and Figure 3.

V <sub>gs</sub> (V vs. Li/Li <sup>+</sup> )	R (Ω) Forward	R (Ω) Backward
0.0 V (3.0 V vs. Li/Li <sup>+</sup> )	340	310
-0.4 V (3.4 V vs. Li/Li <sup>+</sup> )	336	312
-0.8 V (3.8 V vs. Li/Li <sup>+</sup> )	318	310
-1.2 V (4.2 V vs. Li/Li <sup>+</sup> )	302	303
-1.6 V (4.6 V vs. Li/Li <sup>+</sup> )	292	290



**Figure S7.** Output curves of LNMO-based IGTs at  $V_{ds}$  scan rate of 20 mV s<sup>-1</sup> for: **a)** forward scan with  $V_{gs}$  from 0 to -1.4 V, corresponding to potentials from 3 to 4.4 V vs Li<sup>+</sup>/Li; **b)** reverse scan with  $V_{gs}$  from -1.4 to 0 V, corresponding to potentials from 4.4 to 3 V vs Li<sup>+</sup>/Li. Related to Figure 2 and Figure 4.

**Table S2**. LNMO composite electronic resistance evaluated from the output tests at different  $V_{gs}$  during forward and backward  $V_{ds}$  sweeps at 20 mV s<sup>-1</sup>, reported in Fig. S7. Related to Figure 2 and Figure 4.

V <sub>gs</sub> (V vs. Li/Li <sup>+</sup> )	R (Ω) Forward	R(Ω) Backward
0.0 V (3.0 V vs. Li/Li <sup>+</sup> )	412	417
-0.4 V (3.4 V vs. Li/Li+)	389	400
-0.6 V (3.6 V <i>vs.</i> Li/Li <sup>+</sup> )	375	380
-1.0 V (3 V vs. Li/Li <sup>+</sup> )	365	363
-1.4 V (4.4 V vs. Li/Li <sup>+</sup> )	351	346